

## UF9640Z

## -11A, -200V P-CHANNEL POWER MOSFET

#### DESCRIPTION

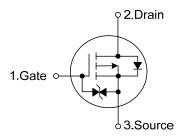
The **UF9640Z** is a P-channel Power MOSFET that developed by UTC's advanced technlogy. The device has an advantage of including fast switching, low on-resistance, ruggedized device design and low cost-effectiveness.

This type of package is generally applied in applications in the commercial-industrial field especially suitable for the power consumption at approximately 50W. Because of its low package cost and low thermal resistance, this package is widely applied in the industry field.

#### FEATURES

- \* Fast switching speed
- \* Repetitive avalanche rated
- \* Simple drive requirements
- \* Ease of paralleling

#### SYMBOL







TO-220F

### **Power MOSFET**

#### ■ **ABSOLUTE MAXIMUM RATINGS** (T<sub>c</sub>=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Gate to Source Voltage		V <sub>GSS</sub>	±20	V
Drain Current	Continuous	I <sub>D</sub>	-11	А
	Pulsed (Note 1)	I <sub>DM</sub>	-22	А
Avalanche Energy	Single Pulsed (Note 2)	E <sub>AS</sub>	35	mJ
	Repetitive (Note 1)	E <sub>AR</sub>	13	mJ
Peak Diode Recovery dv/dt (Note 3)		dv/dt	1.2	V/ns
Power Dissipation		PD	38	W
Junction Temperature		TJ	+150	°C
Storage Temperature		T <sub>STG</sub>	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 3. L=12mH, I<sub>AS</sub>=-2.4A, V<sub>DD</sub>=-50V, R<sub>G</sub>=25 $\Omega$ , Starting T<sub>J</sub> = 25°C.
- 4.  $I_{SD} \leq -11A$ , di/dt  $\leq 200A/\mu$ s,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J=25^{\circ}C$ .

#### THERMAL DATA

PARAMETER	SYMBOL	PATINGS	UNIT	
Junction to Ambient	$\theta_{JA}$	62.5	°C/W	
Junction to Case	θ <sub>JC</sub>	3.31	°C/W	

#### ELECTRICAL CHARACTERISTICS (T<sub>J</sub>=25°C, unless otherwise specified)

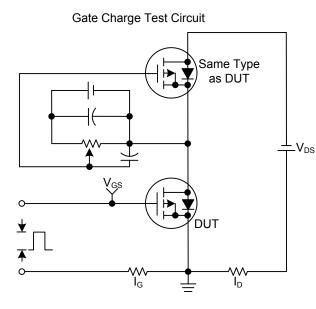
				-		-	-
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		V <sub>(BR)DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =-250µA	-200			V
Drain-Source Leakage Current		I <sub>DSS</sub>	V <sub>DS</sub> =-200V, V <sub>GS</sub> =0V			-10	μA
Gate-Source Leakage Current	Forward	- I <sub>GSS</sub>	V <sub>GS</sub> =+20V			10	μA
	Reverse		V <sub>GS</sub> =-20V			-10	μA
ON CHARACTERISTICS							
Gate Threshold Voltage		V <sub>GS(TH)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =-250µA	-2.0		-4.0	V
Drain-Source On-State Resistance		R <sub>DS(ON)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-6.6A (Note 2)			0.5	Ω
DYNAMIC PARAMETERS							
Input Capacitance		C <sub>ISS</sub>			770		pF
Output Capacitance		Coss	V <sub>DS</sub> =-25V,V <sub>GS</sub> =0V,f=1.0MHz		185		pF
Reverse Transfer Capacitance		C <sub>RSS</sub>			20		pF
SWITCHING PARAMETERS							
Total Gate Charge		$Q_{G}$	V <sub>DS</sub> =-50V, V <sub>GS</sub> =-10V, I <sub>D</sub> =-1.3A, I <sub>G</sub> =-100mA (Note 2)		7.0		nC
Gate-Source Charge		$Q_{GS}$			6.8		nC
Gate-Drain Charge		$Q_{GD}$	$I_{D}$ = 1.3A, $I_{G}$ = 100IIIA (Note 2)		8.4		nC
Turn-ON Delay Time		t <sub>D(ON)</sub>			11		ns
Turn-ON Rise Time		t <sub>R</sub>	$V_{DD}$ =-50V, $V_{GS}$ =-10 $\Omega$ , $I_{D}$ =-5A,		19		ns
Turn-OFF Delay Time		t <sub>D(OFF)</sub>	R <sub>G</sub> =25Ω (Note 2)		58		ns
Turn-OFF Fall Time		t <sub>F</sub>			25		ns
SOURCE- DRAIN DIODE RATI	NGS AND C	CHARACTERI	STICS				
Maximum Body-Diode Continuous Current		Is	A 112	2		-11	Α
Maximum Body-Diode Pulsed Current		I <sub>SM</sub>	SPL CO	) ( )		-22	Α
Drain-Source Diode Forward Voltage		V <sub>SD</sub>	I <sub>S</sub> =-11A, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			-5.0	V
Body Diode Reverse Recovery Time		t <sub>rr</sub>	I <sub>F</sub> =-11A, T <sub>J</sub> =25°C		260		ns
Body Diode Reverse Recovery Charge		Qrr	dl/dt=100A/µs (Note 2)		1.6		μC
Notes: 1 Pulse width limited by	maximum ii	inction temper:	ature				

Notes: 1. Pulse width limited by maximum junction temperature

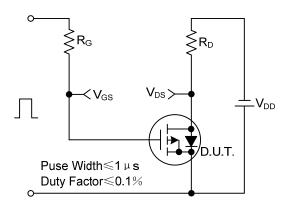
2. Pulse Test : Pulse width≤300µs, Duty cycle≤2%



#### TEST CIRCUITS AND WAVEFORMS



**Resistive Switching Test Circuit** 

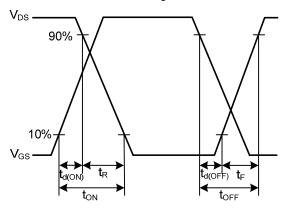


Unclamped Inductive Switching Test Circuit

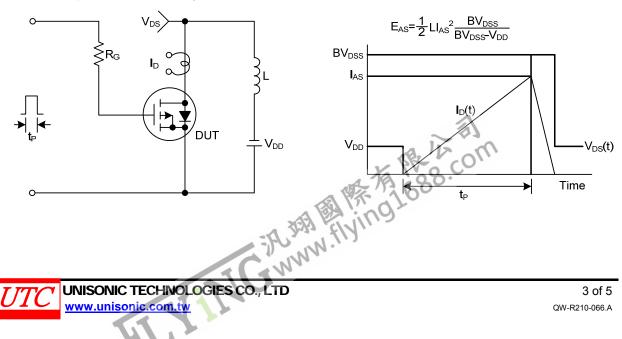
V<sub>GS</sub> Q<sub>G</sub> Q<sub>G</sub> Q<sub>G</sub> Q<sub>G</sub> Charge

Gate Charge Waveforms

**Resistive Switching Waveforms** 



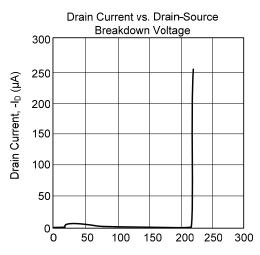
**Unclamped Inductive Switching Waveforms** 



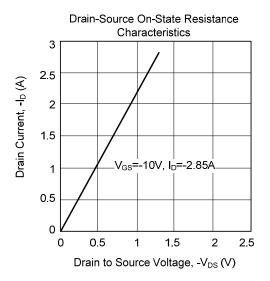
# UF9640Z

### **Power MOSFET**

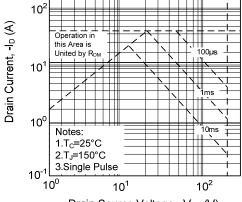
#### TYPICAL CHARACTERISTICS

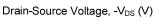


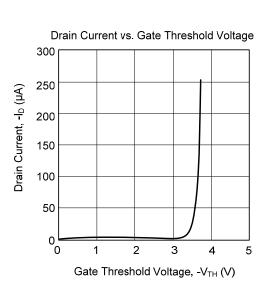
Drain-Source Breakdown Voltage, -BV<sub>DSS</sub>(V)



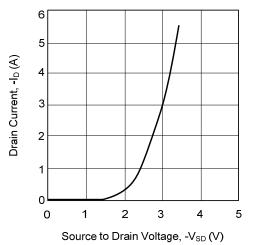








Drain Current vs. Source to Drain Voltage





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